

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/766,005	TANAKA, SHINJI	
Examiner	Art Unit	
Jordany Núñez	2179	

	SEAR	CHED	
Class	Subclass	Date	Examiner
715	722	8/14/2006	JN
	,		
	· 		N
	1		
	1		

INT	ERFERENC	E SEARCH	ED
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
East: USPAT, US PGPUB, EPO, JPO, Derwent, IBM-IDB	8/14/2006	JN		
NPL	8/14/2006	ΝĹ		
Consulted with primary examiner, Ba Huynh, AU 2179	8/14/2006	ΝĹ		